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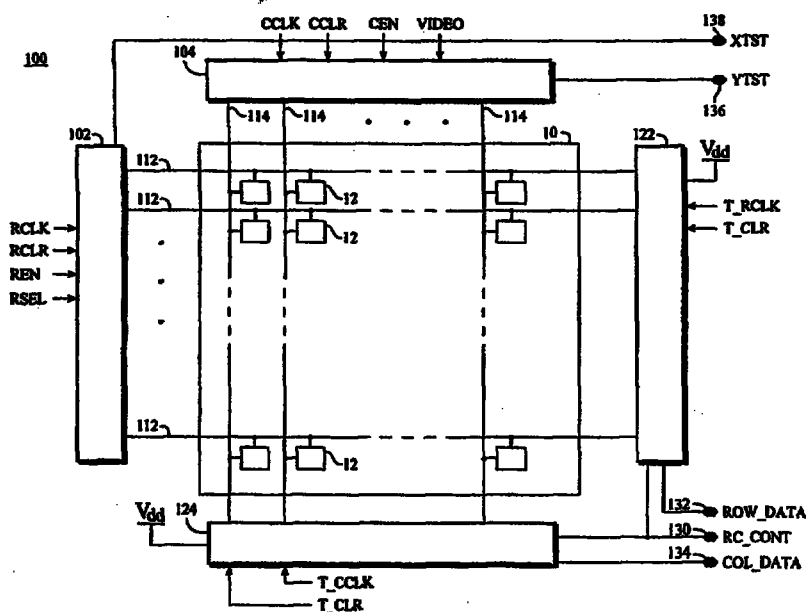
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(54) Title: **METHOD AND APPARATUS FOR TESTING A VIDEO DISPLAY CHIP**



(57) Abstract: A video chip (100) includes test circuitry for detecting opens and shorts. The circuitry includes a series-connected chain of transistors and a test register (122, 124). There is a circuit for the column lines (114) and for the row lines (112). A bit pattern is driven onto the column (114) or the row lines (112) and received in the corresponding test circuitry. The pattern is read out and compared against the input pattern to detect faulty lines.

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